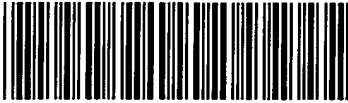


Search Notes

Application/Control No.

10/765,311

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

WENDELL ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PG PUB search		02-04-06	ASZ

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See attachment	02.04.06	AN